

March 2013

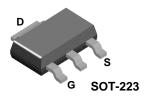
# FQT13N06L N-Channel QFET® MOSFET 60 V, 2.8 A, 140 m $\Omega$

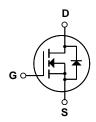
## **Description**

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

#### **Features**

- 2.8 A, 60 V,  $R_{DS(on)}$ =140 m $\Omega(Max.)$  @ $V_{GS}$ =10 V,  $I_D$ =1.4 A
- Low Gate Charge (Typ. 4.8 nC)
- Low Crss (Typ. 17 pF)
- 100% Avalanche Tested





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQT13N06L	Unit	
V <sub>DSS</sub>	Drain-Source Voltage		60	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		2.8	А	
	- Continuous (T <sub>C</sub> = 70°C)		2.24	А	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	11.2	А	
$V_{GSS}$	Gate-Source Voltage		± 20	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	85	mJ	
I <sub>AR</sub>	Avalanche Current (Note 1		2.8	А	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	0.21	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		7.0	V/ns	
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C)		2.1	W	
	- Derate above 25°C		0.017	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes,  1/8" from case for 5 seconds		300	°C	
٠.			300		

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		60	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	i	Min	Тур	Max	Unit
Off Cha	aracteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced	to 25°C		0.05		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V				1	μА
		V <sub>DS</sub> = 48 V, T <sub>C</sub> = 125°C				10	μA
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics		"		1		
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		1.0		2.5	V
R <sub>DS(on)</sub>	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 1.4 \text{ A}$			0.088	0.11	
. (DS(on)	On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 1.4 \text{ A}$			0.110	0.14	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 25 V, I <sub>D</sub> = 1.4 A	(Note 4)		4.1		S
<b>Dynam</b> C <sub>iss</sub>	ic Characteristics Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,			270	350	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz			95	125	pF
C <sub>rss</sub>	Reverse Transfer Capacitance				17	23	pF
Switchi	ing Characteristics						
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 30 \text{ V}, I_{D} = 6.8 \text{ A},$ $R_{G} = 25 \Omega$			8	25	ns
t <sub>r</sub>	Turn-On Rise Time				90	190	ns
t <sub>d(off)</sub>	Turn-Off Delay Time				20	50	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)		40	90	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 48 V, I <sub>D</sub> = 13.6 A,			4.8	6.4	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 5 V (Note 4, 5)			1.6		nC
Q <sub>gd</sub>	Gate-Drain Charge				2.7		nC
Drain-S	Source Diode Characteristics a	nd Maximum Rating	S				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current					2.8	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	Forward Current				11.2	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.8 \text{ A}$				1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 13.6 \text{ A},$			45		ns
	i e e e e e e e e e e e e e e e e e e e	4	(Note 4)				

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 12.6mH, I<sub>AS</sub> = 2.8A, V<sub>DD</sub> = 25V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  13.6A, di/dt  $\leq$  300A/μs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300µs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

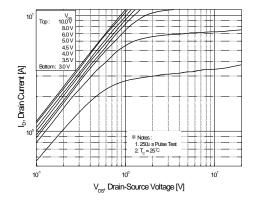


Figure 1. On-Region Characteristics

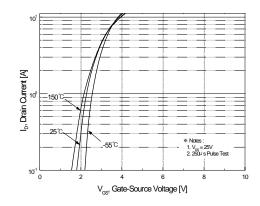


Figure 2. Transfer Characteristics

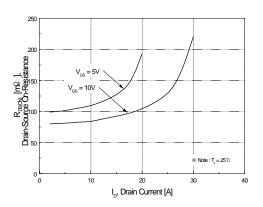


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

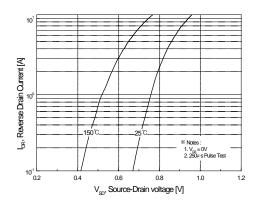


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

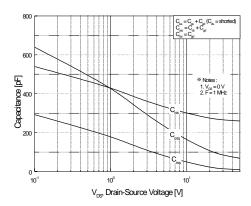


Figure 5. Capacitance Characteristics

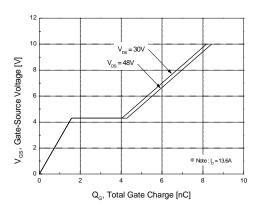
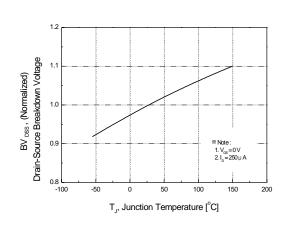


Figure 6. Gate Charge Characteristics



Typical Characteristics (Continued)

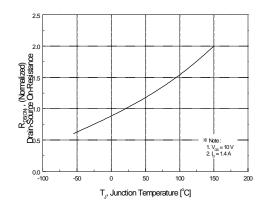
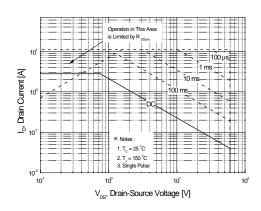


Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



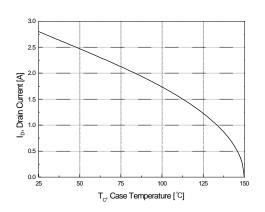


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

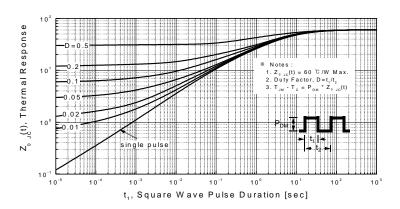
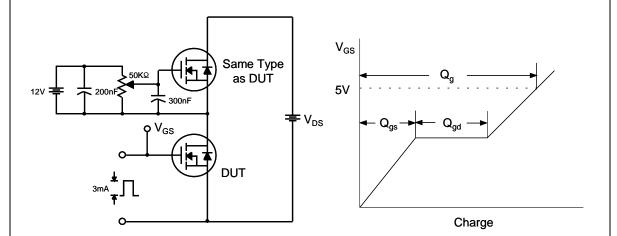
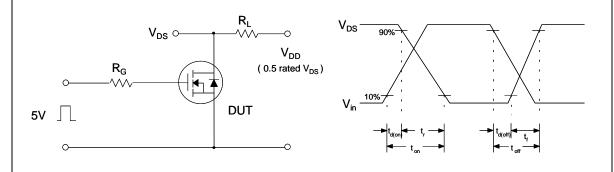


Figure 11. Transient Thermal Response Curve

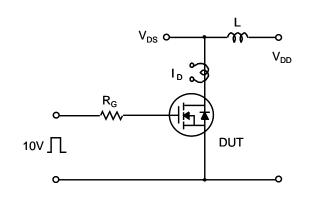
#### **Gate Charge Test Circuit & Waveform**

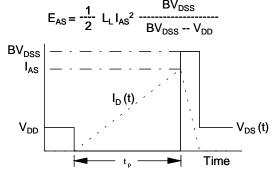


## **Resistive Switching Test Circuit & Waveforms**

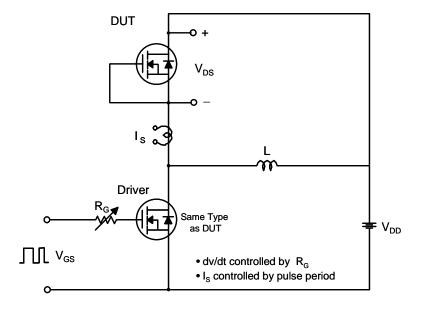


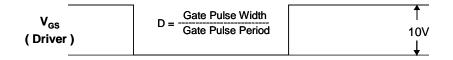
## **Unclamped Inductive Switching Test Circuit & Waveform**

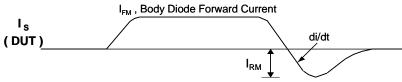




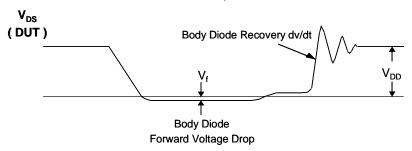
#### Peak Diode Recovery dv/dt Test Circuit & Waveform

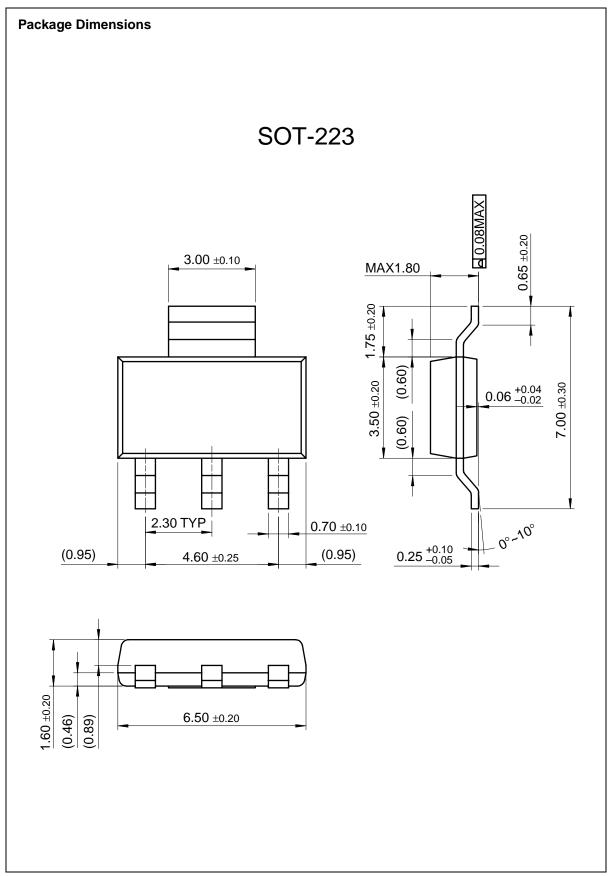






Body Diode Reverse Current









#### **TRADEMARKS**

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

FPS™ AccuPower™ F-PFS™ AX-CAP®\* FRFET® BitSiC™ Global Power Resource<sup>SM</sup> Build it Now™ Green Bridge™

Green FPS™ CorePLUS™ CorePOWER™ Green FPS™ e-Series™ CROSSVOLT<sup>TM</sup> Gmax™

GTO™ CTL™ Current Transfer Logic™ IntelliMAX™ DEUXPEED<sup>®</sup> ISOPLANAR™

Dual Cool™ Marking Small Speakers Sound Louder EcoSPARK® and Better™

MegaBuck™ EfficentMax™ ESBC™ MICROCOUPLER™ MicroFET™

MicroPak™ MicroPak2™ MillerDrive™ MotionMax™

FACT Quiet Series™ mWSaver™ FACT® OptoHiT™ FAST® OPTOLOGIC® FastvCore™ OPTOPLANAR® FETBench™

PowerTrench® PowerXS™

Programmable Active Droop™

QS™ Quiet Series™ RapidConfigure™

ng our world, 1mW/W/kW at a time™ SignalWise<sup>TM</sup>

SmartMax™ SMART START™

Solutions for Your Success™

SPM STEALTH™ SuperFET® SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS<sup>®</sup> SyncFET™

Sync-Lock™ SYSTEM ®\* TinyBoost™ TinyBuck™ TinyCalc™ TinyLogic<sup>®</sup> TIŃYOPTO™ TinyPower™ TinyPWM™ TinyWire™ TranSiC® TriFault Detect™ TRUECURRENT®\* μSerDes™

UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ VoltagePlus™

\*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

#### DISCLAIMER

Fairchild®

Fairchild Semiconductor®

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN: NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS. NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN. WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY
FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

#### PRODUCT STATUS DEFINITIONS **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. 164